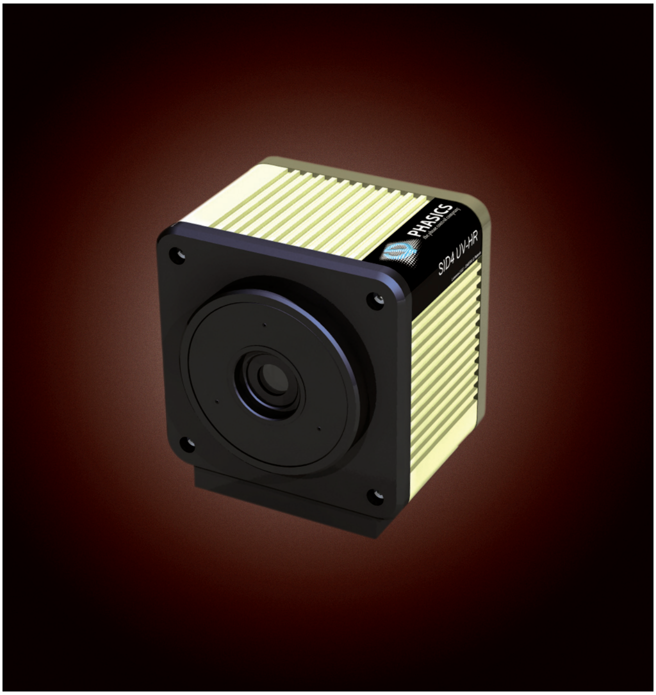
SID4 UV-HR
WAVE FRONT SENSOR



PHASICS extends the SID4 product line to UV wavelengths. With the **SID4 UV-HR**, all the advantages of the PHASICS technology (4-wave lateral shearing Interferometry*) are accessible from 190 nm to 400 nm.

The sampling resolution of 250 x 250 measurement points is adapted for **optical components characterization** (used in lithography, semiconductor...) and also in **surface inspection** (wafers inspection for instance).

With such sensitivity, SID4 UV-HR is the cost effective UV solution for high resolution characterization.

SPECIFICATIONS

Aperture dimension	8.0 x 8.0 mm^2
Spatial resolution	32 μm
Sampling	250 x 250
Wavelength range	190 - 400 nm
Accuracy (absolute)	10 nm
Sensitivity	0.5 nm
Dynamic	$> 200\ \mu m$
Radius of curvature	10 mm to $+\infty$
Sensitivity curvature measurement	$< 5.\ 10^{-4}\ m^{-1}$
Analysis rate	1 fps
Acquisition rate	30 fps
Dimensions (l x H x L)	95 x 105 x 84 mm
Weight	900 g

KEY FEATURES

- Very high resolution (250 x 250)
- Large analysis pupil (8,0 mm x 8,0 mm)
- UV spectrum covered
- High sensitivity (0,5 nm)
- Optimal signal to noise ratio
- Adapted to optics characterization

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